SHEET 1 OF 1

INFO	CIT	ATION DISCLO FATION IN AN PPLICATION	ATTY, DOCKET NO. 60188-400		SERIAL NO. 09/964,868				
				APPLICANT TAMAKI, TOKUHIKO, et al.					
(PTO-1449)				FILING DATE					
			September 28, 200	L					
			U.S. PATE	NT DOCUMENTS					
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		10 444000 44 111 11					Yes	No	
)u	A	JP 03180041 with English abstract		Seiko Epson Corp.	<u> </u>				
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